

**Notice of References Cited**

Application/Control No.

10/603,433

Applicant(s)/Patent Under  
Reexamination  
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2881

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,591,971	01-1997	Shahar et al.	250/310
	B	US-6,444,981	09-2002	Todokoro et al.	250/310
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Winkler et al., "Apparatus and Method for Examining Specimen with Charged Particle Beam", Pub. No: 2002/0053638 A1, Publication date: May 9, 2002.
	V	
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.